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	Notice of References Cited	Application/Control No.	Applicant(s)/Patent Under		
		09/816,227 Reexamination TANAKA, MASAHII		07	
		Examiner	Art Unit		
		Sam Rimell	2175 Page 1 c	of 1	

**U.S. PATENT DOCUMENTS** 

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6509900	01-2003	Ohsawa et al.	711/160
	В	US-6421141	07-2002	Nishikawa	358/518
	С	US-6434746	08-2002	Nagashima et al.	725/96
	D	US-US2001/0002204	05-2001	Jebens et al.	707/104.1
	E	US-			
	F	US-			
	G	US-			
	Н	US-			
	ı	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
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	Т					

## NON-PATENT DOCUMENTS

	TOTAL PROGRAMMENTO				
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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